

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/526,115 KAARIO ET AL.	
		Examiner	Art Unit Van Kim T. Nguyen	2456 Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0168644	07-2006	Richter et al.	726/002
*	B	US-2001/0054082	12-2001	Rudolph et al.	709/217
*	C	US-7,316,347	01-2008	Poor, David Deas Sinkler	235/375
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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